Notice of References Cited Application/Control No. 10/813,212 Examiner Shin-Hon Chen Applicant(s)/Patent Under Reexamination QUMEI, IYAD Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0051160	03-2003	Selkirk et al.	713/201
*	В	US-6,230,316	05-2001	Nachenberg, Carey	717/169
*	С	US-7,095,858	08-2006	Wagner et al.	380/281
*	D	US-2004/0006703	01-2004	Kitani et al.	713/193
	E	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
-	J	US-			
	к	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.